Docket: 740756-2406

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re I	Divisional Patent Application of)			
Shunp	pei YAMAZAKI et al.)			
Based	On Serial No. 09/172,300) Art Unit: 2813			
Whicl	h Was Filed: October 14, 1998) Examiner: E. Pert			
For:	METHOD OF MANUFACTURING)			
	A SEMICONDUCTOR DEVICE) Date: January 15, 2002			

INFORMATION DISCLOSURE STATEMENT

Honorable Commissioner for Patents and Trademarks Washington, D.C. 20231

Sir:

In accordance with the provisions of 37 C.F.R. 1.56 and 37 C.F.R. 1.97-1.99, it is requested that the references listed on the attached Form PTO-1449 be made of record in the above-identified application.

The references listed on the attached Form PTO-1449 were cited in parent application Serial No. 09/172,300 filed October 14, 1998.

Respectfully submitted,

Eric J. Robinson

Registration No. 38,285

NIXON PEABODY LLP 8180 Greensboro Drive, Suite 800 McLean, Virginia 22102 (703) 790-9110

Sheet 1 of 1

Rev. 8-83) Patent and Trademark Office INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary) Applicant: Shunpei YAMAZAKI et al. Filing Date: January 15, 2002 Group: 2813 U.S. PATENT DOCUMENTS Examiner Initial Document Number Date Name Class Subclass Filing Date (if appropriate 5,648,277 07/15/1997 Zhang et al. 5,643,826 07/01/1997 Ohtani et al. 6,124,154 09/26/2000 Miyasaka 5,550,070 08/27/1996 Funai et al. 6,124,154 09/26/2000 Miyasaka 5,550,070 08/27/1996 Funai et al. FOREIGN PATENT DOCUMENTS Document Number Date Country Class Subclass Translation	Form PTO-1449 U.S. Department of Commerce			Docket No. 740756-2406		Serial No. Not Yet		
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